2SB1063

Silicon PNP triple diffusion planar type

For high power amplification Complementary to 2SD1499

■ Features

- \bullet Extremely satisfactory linearity of the forward current transfer ratio h_{FE}
- Wide safe operation area
- High transition frequency f_T
- Full-pack package which can be installed to the heat sink with one

■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V _{CBO}	-100	V	
Collector-emitter voltage (Base open)	V _{CEO}	-100	V	
Emitter-base voltage (Collector open)	V_{EBO}	- 5	V	
Collector current	Ic	-5	A	
Peak collector current	I_{CP}	-8	A	
Collector power dissipation	P _C	40	W	
$T_a = 25^{\circ}C$		2.0		
Junction temperature	$T_{\rm j}$	150	°C	
Storage temperature	T_{stg}	-55 to +150	°C	
	<u> </u>		_	

Unit: mm φ 3.1±0.1 1.3±0.2 0.5+0.2 3: Emitter EIAJ: SC-67 TO-220F-A1 Package

■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

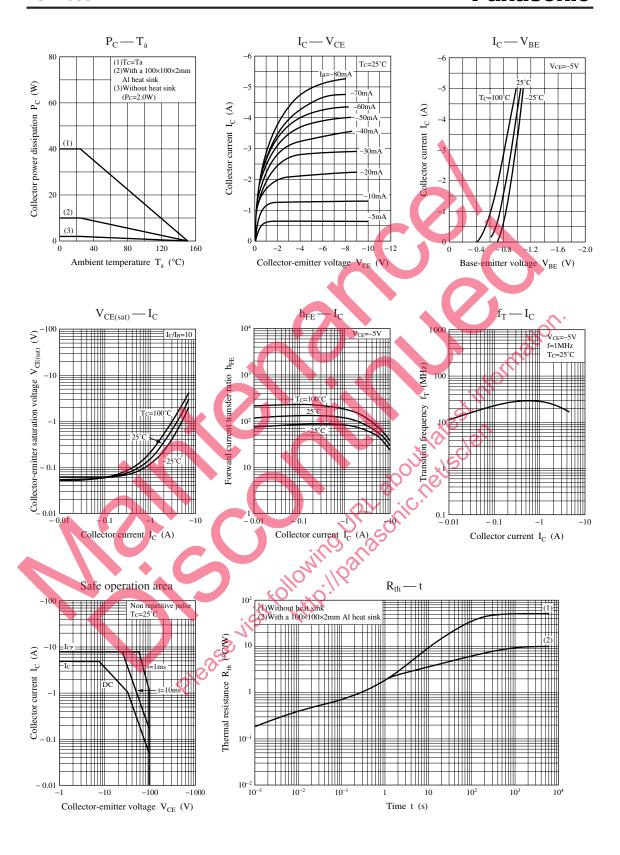
Collector current	I_{C}	-5	A	•	(1)				
Peak collector current	I_{CP}	-8	A	a'					
Collector power dissipation	P _C	40	W	XOS	0				
$T_a = 25^{\circ}C$		2.0	A N	10,	S.				
Junction temperature T _j 150 °C									
Storage temperature T _{stg} -55 to +150 °C									
IRL nic.									
■ Electrical Characteristics T	$c = 25^{\circ}C$	±3°C							
Parameter	Symbol		Conditions	Min	Тур	Max	Unit		
Base-emitter voltage	V_{BE}	$V_{CE} = -5$	$V, I_C = -3 A$			-1.8	V		
Collector-base cutoff current (Emitter open) I_{CBO} $V_{CB} = -100 \text{ V}, I_{E} = 0$						-50	μΑ		
Emitter-base cutoff current (Collector open)	I_{EBO}	$V_{EB} = -3$	$I_{\rm C} = 0$			-50	μΑ		
Forward current transfer ratio	h _{FE1}	$V_{CE} = -5$	$V, I_C = -20 \text{ mA}$	20			_		
	hE2*	$V_{\rm CE} = -5$	$V, I_C = -1 A$	40		200			
	h _{FE3}	$V_{CE} = -5$	$V, I_C = -3 A$	20					
Collector-emitter saturation voltage	V _{CE(sat)}	$I_{\rm C} = -3 \text{ A},$	$I_B = -0.3 \text{ A}$			-2	V		
Transition frequency	f_T	$V_{\rm CE} = -5$	$V, I_C = -0.5 A, f = 1 MHz$		20		MHz		
Collector output capacitance	C _{ob}	$V_{CB} = -10$	$V, I_E = 0, f = 1 \text{ MHz}$		170		pF		
(Common base, input open circuited)									

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. *: Rank classification

Rank	R	Q	Р
h _{FE2}	40 to 80	60 to 120	100 to 200

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